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N-channel TrenchMOS logic level FET

Rev. 03 — 15 June 2010

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant

sources Suitable for thermally demanding

Suitable for logic level gate drive

1.3 Applications

- 12 V and 24 V loads
- Automotive systems

General purpose power switching

environments due to 175 °C rating

Motors, lamps and solenoids

1.4 Quick reference data

Table 1. C	Quick ref	ference o	lata
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Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	55	V
I _D	drain current	V _{GS} = 5 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	<u>[1]</u>	-	-	75	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	203	W
Static cha	racteristics						
R _{DSon}	drain-source on-state	V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C		-	6.2	7	mΩ
	resistance	$\label{eq:VGS} \begin{array}{l} V_{GS} = 5 \text{ V}; \text{ I}_D = 25 \text{ A}; \\ T_j = 25 \text{ °C}; \\ \text{see } \underline{\text{Figure 11}}; \text{ see } \underline{\text{Figure 12}} \end{array}$		-	7.1	8.4	mΩ



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Table 1.	Quick reference data continued					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 75 \text{ A}; V_{sup} \leq 55 \text{ V}; \\ R_{GS} &= 50 \Omega; V_{GS} = 5 \text{ V}; \\ T_{j(init)} &= 25 ^\circ\text{C}; \text{unclamped} \end{split} $	-	-	352	mJ
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$V_{GS} = 5 V; I_D = 25 A;$ $V_{DS} = 44 V; T_j = 25 °C;$ see Figure 13	-	16	-	nC

[1] Continuous current is limited by package.

2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		2
2	D	drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

SOT78 (TO-220AB)

3. Ordering information

Table 3.	Ordering	information
	e ao ing	

Type number	Package		
	Name	Description	Version
BUK9508-55B	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

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4. Limiting values

Table 4. Limiting values

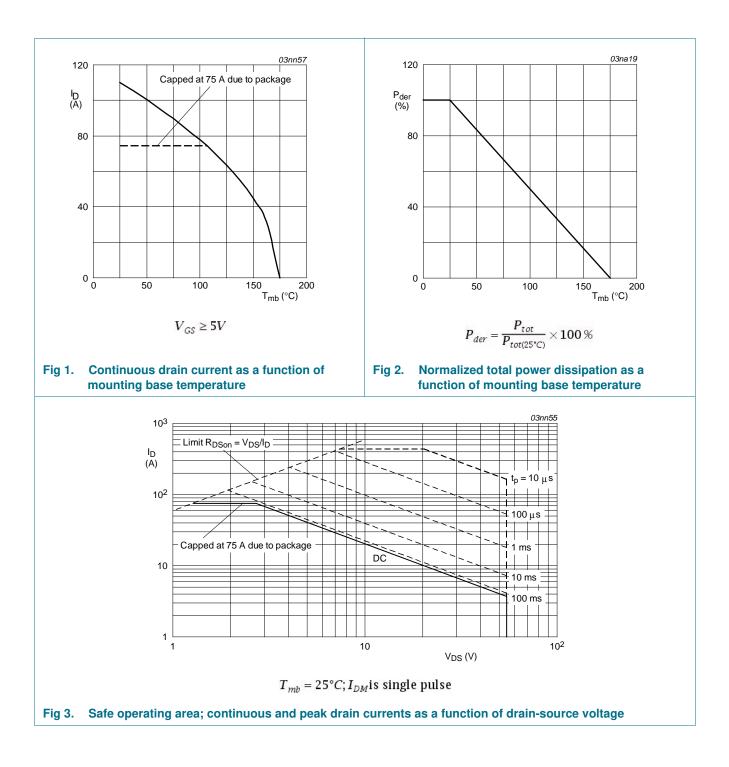
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	55	V
V _{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	-	55	V
V _{GS}	gate-source voltage			-15	-	15	V
I _D	drain current	T_{mb} = 100 °C; V_{GS} = 5 V; see <u>Figure 1</u>	<u>[1]</u>	-	-	75	А
		$T_{mb} = 25 \text{ °C}; V_{GS} = 5 \text{ V}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 1}};$	[2]	-	-	110	А
		see <u>Figure 3</u>	<u>[1]</u>	-	-	75	А
I _{DM}	peak drain current	T_{mb} = 25 °C; $t_p \le 10 \ \mu$ s; pulsed; see <u>Figure 3</u>		-	-	439	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	203	W
T _{stg}	storage temperature			-55	-	175	°C
Tj	junction temperature			-55	-	175	°C
Source-drain	diode						
I _S	source current	T _{mb} = 25 °C	[2]	-	-	110	А
			[1]	-	-	75	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	-	439	А
Avalanche rug	ggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$\label{eq:ID} \begin{array}{l} I_D = 75 \text{ A}; \ V_{sup} \leq 55 \text{ V}; \ R_{GS} = 50 \ \Omega; \\ V_{GS} = 5 \text{ V}; \ T_{j(init)} = 25 \ ^\circ\text{C}; \ unclamped \end{array}$		-	-	352	mJ

[1] Continuous current is limited by package.

[2] Current is limited by power dissipation chip rating.

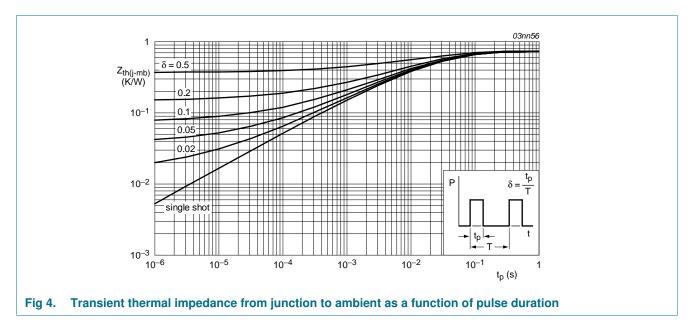
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5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-mb)}}$	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	0.74	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W



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6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	55	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	50	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 25 °C; see <u>Figure 10</u>	1.1	1.5	2	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 10</u>	-	-	2.3	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 175 °C; see <u>Figure 10</u>	0.5	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μA
I _{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; \text{ V}_{GS} = 15 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	2	100	nA
		V _{DS} = 0 V; V _{GS} = -15 V; T _j = 25 °C	-	2	100	nA
R _{DSon}	drain-source on-state	V _{GS} = 4.5 V; I _D = 25 A; T _j = 25 °C	-	-	9.3	mΩ
	resistance	V _{GS} = 5 V; I _D = 25 A; T _j = 175 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	-	16.8	mΩ
		V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C	-	6.2	7	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 11; see Figure 12	-	7.1	8.4	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 5 \text{ V};$	-	45	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 13</u>	-	9	-	nC
Q _{GD}	gate-drain charge		-	16	-	nC
C _{iss}	input capacitance	V _{GS} = 0 V; V _{DS} = 25 V; f = 1 MHz;	-	3960	5280	pF
C _{oss}	output capacitance	T _j = 25 °C; see Figure 14	-	517	620	pF
C _{rss}	reverse transfer capacitance		-	206	282	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 5 \text{ V};$	-	29	-	ns
t _r	rise time	$R_{G(ext)} = 10 \ \Omega; T_j = 25 \ ^{\circ}C$	-	123	-	ns
t _{d(off)}	turn-off delay time		-	131	-	ns
t _f	fall time		-	86	-	ns
L _D	internal drain inductance	from drain lead 6 mm from package to center of die ; $T_j = 25 \text{ °C}$	-	4.5	-	nH
		from contact screw on mounting base to center of die ; $T_j = 25 \text{ °C}$	-	3.5	-	nH
L _S	internal source inductance	from source lead to source bond pad ; $T_j = 25 \ ^{\circ}C$	-	7.5	-	nH

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Symbol

Source-drain diode

BUK9508-55B

Мах

Unit

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Тур

Min

SD	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}$ see <u>Figure 15</u>	/; T _j = 25 °C;	-	0.85	1.2	V
	reverse recovery time	$I_{\rm S} = 20 \text{ A}; dI_{\rm S}/dt = -1$		-	69	-	ns
r	recovered charge	V _{GS} = -10 V; V _{DS} = 5	30 V; T _j = 25 °C	-	72	-	nC
300	5, 4.8 Labe	03nn52	25 R _{DSon}			03nn51	
I _D (A) —	10 4.4		(mΩ) 20				
200 -	4.2		15				
100 -	3.8		10				
			5				
0 K			0	5	10 ,	15	
0	2 4 6	8 10 V _{DS} (V)	0	5	V _G	s (V) 13	
0	2 4 6 $T_j = 25^{\circ}C; t_p = 300\mu$	V _{DS} (V)	0	5 T _j = 25°C;1	V _G	_S (V)	
0 ig 5. O		V _{DS} (V) IS	Fig 6. Drain-so		V_{GS} $T_D = 25A$ e resistance	e as a fu	unction
0 iig 5. Of fu	$T_j = 25^{\circ}C; t_p = 300\mu$ Dutput characteristics: drain	V _{DS} (V) IS	Fig 6. Drain-so	$T_j = 25^{\circ}C;I$ urce on-state	V_{GS} $T_D = 25A$ e resistance	e as a fu	unctior
0 Fig 5. O fu	$T_j = 25^{\circ}C; t_p = 300\mu$ Dutput characteristics: drain	V _{DS} (V) <i>IS</i> a current as a age; typical values	Fig 6. Drain-so of gate-s	$T_j = 25^{\circ}C;I$ urce on-state	V_{GS} $T_D = 25A$ e resistance	e as a fu /alues	unctior
0 Fig 5. Of fu	$T_j = 25^{\circ}C; t_p = 300\mu$ Dutput characteristics: drain	V _{DS} (V) <i>IS</i> age; typical values 03ng53	Fig 6. Drain-so of gate-s	$T_j = 25^{\circ}C;I$ urce on-state	V_{GS} $T_D = 25A$ e resistance	e as a fu /alues	unctior
0 Fig 5. Of fu 10 ⁻¹ Ib (A) 10 ⁻²	$T_j = 25^{\circ}C; t_p = 300\mu$ Supput characteristics: drain unction of drain-source volt	V _{DS} (V) <i>IS</i> age; typical values 03ng53	Fig 6. Drain-so of gate-so 120 g _{fs} (S)	$T_j = 25^{\circ}C;I$ urce on-state	V_{GS} $T_D = 25A$ e resistance	e as a fu /alues	Inctior
0 Fig 5. Of fu (A) 10 ⁻¹ (A) 10 ⁻²	$T_{j} = 25^{\circ}C; t_{p} = 300\mu$ Dutput characteristics: drainunction of drain-source volt	V _{DS} (V) <i>IS</i> age; typical values 03ng53	Fig 6. Drain-so of gate-s	$T_j = 25^{\circ}C;I$ urce on-state	V_{GS} $T_D = 25A$ e resistance	e as a fu /alues	unction
0 Fig 5. Or fu (A) 10 ⁻² 10 ⁻³	$T_j = 25^{\circ}C; t_p = 300\mu$ Dutput characteristics: drain function of drain-source volt	V _{DS} (V) <i>IS</i> age; typical values 03ng53	Fig 6. Drain-so of gate-s	$T_j = 25^{\circ}C;I$ urce on-state	V _G	e as a fu /alues	
0 fig 5. Of 10 ⁻¹ b (A) 10 ⁻² 10 ⁻³ 10 ⁻⁴	$T_j = 25^{\circ}C; t_p = 300\mu$ Dutput characteristics: drain unction of drain-source volt $\frac{1}{1}$	V _{DS} (V) // / / / / / / / / / / / /	Fig 6. Drain-so of gate-so g _{fs} (S) 80 40 40 0 0	T _j = 25°C;I	V_{GS}	e as a fu	

Table 6. Characteristics ...continued

Parameter

Conditions

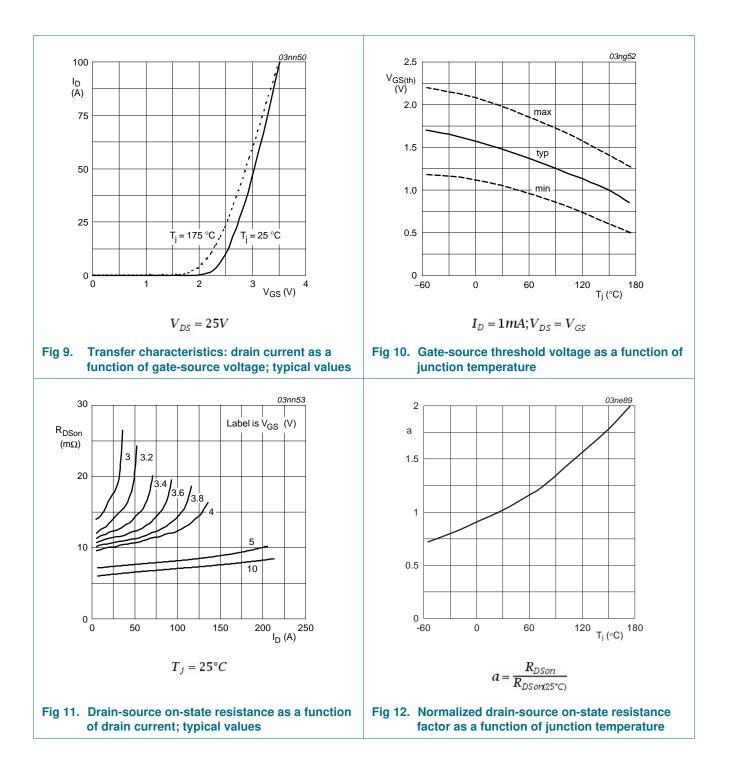
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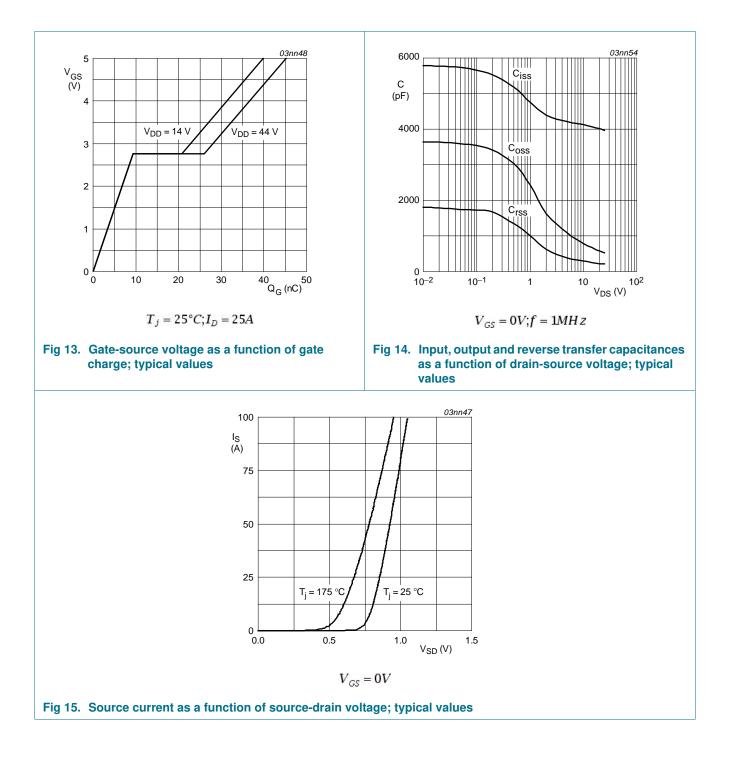
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Package outline 7.

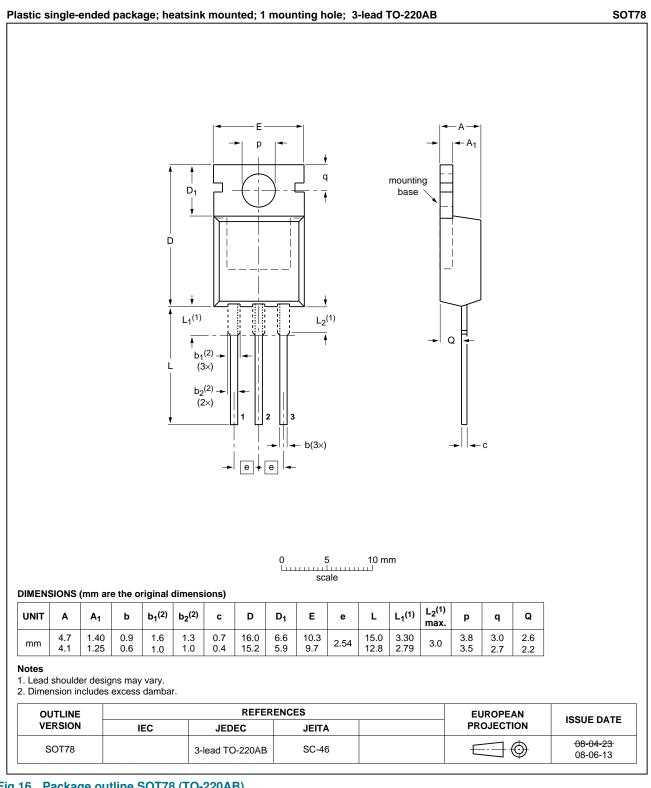


Fig 16. Package outline SOT78 (TO-220AB)

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8. Revision history

Table 7. Revision his	story			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK9508-55B v.3	20100615	Product data sheet	-	BUK95_96_9E08 v.2
Modifications:		of this data sheet has be niconductors.	een redesigned to comply	with the new identity guidelines
	 Legal texts 	have been adapted to t	he new company name wł	nere appropriate.
	 Type numb 	er BUK9508-55B separa	ated from data sheet BUK	95_96_9E08 v.2.
BUK95_96_9E08 v.2 (9397 750 12052)	20030313	Product data	-	-

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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[2] The term 'short data sheet' is explained in section "Definitions".

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